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SHEET 1 OF 1

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT LIST OF REFERENCES CITED BY APPLICANT Vouichi NISHIMURO, et al. FILING DATE GROUP March 18, 2002 U.S. PATENT DOCUMENTS EXAMINER INITIAL NUMBER DOCUMENT DATE NAME CLASS SUB FILING DA IF APPROPR AA 6,027,211 D2/22/2000 UNOSAWA et al.		
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FOREIGN PATENT DOCUMENTS		
DOCUMENT DATE COUNTRY TRANSLATION YES NO)	
AO 9-110256 04/28/1997 JAPAN (with English Abstract)		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)		
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AZ Additional References sheet(s) a	tached	
Examiner Plea Date Considered 1/8/-		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		